## AMENDMENTS TO THE CLAIMS

Please amend the claims as indicated in the following listing of all claims:

- 1. (Currently Amended) A non-volatile memory cell array comprising within a first array block a first plurality of X-lines configured to be simultaneously selected logically identical in a read mode of operation, and each associated with a first Y-line group numbering at least one Y-line.
- 2. (Original) The memory array as recited in claim 1 wherein each of the first plurality of X-lines is also associated with a second Y-line group numbering at least one Y-line.
- 3. (Currently Amended) The memory array as recited in claim 2 wherein the first and second <u>Y-line</u> <del>Y-Line</del> groups are simultaneously selectable in a read mode and, when so selected, are respectively coupled to true and complement inputs of a sense amplifier circuit.
- 4. (Original) The memory array as recited in claim 3 wherein the first and second Y-line groups each numbers only one Y-line.
- 5. (Original) The memory array as recited in claim 3 wherein the first and second Y-line groups each numbers more than one Y-line.
- 6. (Original) The memory array as recited in claim 3 further comprising a reference signal operably coupled to either the true or complement input of the sense amplifier, wherein the first and second Y-line groups each numbers more than one Y-line.
- 7. (Original) The memory array as recited in claim 6 wherein the reference signal comprises a reference current.
  - 8. (Currently Amended) The memory array as recited in claim 1 wherein: the first Y-line group includes more than one Y-line; and each of the first Y-line group is configured to be simultaneously selected logically identical in a read mode of operation.

- 9. (Currently Amended) The memory array as recited in claim 1 wherein each of the first plurality of X-lines is configured to be individually selected logically independent in a write mode of operation.
- 10. (Original) The memory array as recited in claim 1 wherein the memory array comprises passive element memory cells.
- 11. (Original) The memory array as recited in claim 10 wherein the memory array comprises anti-fuse memory cells.
- 12. (Original) The memory array as recited in claim 10 wherein the memory array comprises magnetoresistive memory cells.
- 13. (Original) The memory array as recited in claim 1 wherein the memory array comprises EEPROM memory cells.
- 14. (Original) The memory array as recited in claim 1 wherein the memory array comprises a two-dimensional memory array having one plane of memory cells.
- 15. (Original) The memory array as recited in claim 1 wherein the memory array comprises a three-dimensional memory array having more than one plane of memory cells.
- 16. (Original) The memory array as recited in claim 15 wherein the first plurality of X-lines comprises X-lines disposed on more than one layer of the memory array.
- 17. (Currently Amended) The memory array as recited in claim 15 wherein the first plurality of X-lines comprises X-lines disposed only on a single layer of the memory array.
- 18. (Original) The memory array as recited in claim 2 configured to perform threshold logic upon one or more inputs to the array.

- 19. (Currently Amended) The memory array as recited in claim 1 further comprising a second plurality of X-lines configured to be <u>simultaneously selected</u> logically identical in a read mode of operation and each associated with the first Y-line group.
- 20. (Currently Amended) The memory array as recited in claim 19 further comprising a third plurality of X-lines associated with the first Y-line group, said third plurality of X-lines being configured, in a read mode of operation, to be <u>simultaneously selected at certain times</u> when logically identical with each other and complementary to the first plurality of X-lines is not selected.
  - 21. (Currently Amended) The memory array as recited in claim 20 further comprising: a fourth plurality of X-lines associated with the first Y-line group, said fourth plurality of X-lines being configured, in a read mode of operation, to be <u>simultaneously</u> selected when <u>logically identical with each other and complementary to</u> the second plurality of X-lines <u>is not selected</u>; and
  - a second Y-line group numbering at least one Y-line, each of which is associated with the first, second, third, and fourth pluralities of X-lines.
- 22. (Original) The memory array as recited in claim 19 configured to perform threshold logic upon one or more inputs to the array.
- 23. (Original) The memory array as recited in claim 19 configured to perform weighted input threshold logic upon one or more inputs to the array.
- 24. (Original) The memory array as recited in claim 1 wherein X-lines comprise word lines.
  - 25. (Canceled)
- 26. (Original) The memory array as recited in claim 1 configured as a content addressable memory array.

- 27. (Currently Amended) The memory array as recited in claim 2 wherein:

  each of the first Y-line group is configured to be simultaneously selected logically

  identical in a read mode of operation; and

  each of the second Y-line group is configured to be simultaneously selected logically

  identical in a read mode of operation.
- 28. (Original) The memory array as recited in claim 1 embodied in computer readable descriptive form suitable for use in design, test or fabrication of an integrated circuit.
- 29. (Currently Amended) A method of operating a non-volatile memory array comprising:
  - X-line within a first array block and further associated with a first Y-line group of at least one Y-line within the first array block until a desired first aggregate memory cell read current is obtained when simultaneously selecting all the first group of X-lines and all the first group of Y-lines, at least one of the first X-line group and first Y-line group including more than one such X-line or Y-line; and reading the memory array by simultaneously selecting all the first group of X-lines and all the first group of Y-lines and generating a signal responsive to the first aggregate memory cell read current.
  - 30. (Original) The method of claim 29 further comprising:
  - programming individual memory cells associated with the first X-line group and further associated with a second Y-line group of at least one Y-line until a desired second aggregate memory cell read current is obtained when simultaneously selecting all the first group of X-lines and all the second group of Y-lines, which second aggregate memory cell current is greater than the first aggregate memory cell current; and
  - reading the memory array by simultaneously selecting all the first group of X-lines and all the first and second groups of Y-lines and generating a signal responsive to the greater of the first and second aggregate memory cell read current.

- 31. (Original) The method of claim 30 wherein the memory array comprises write-once memory cells.
  - 32. (Original) The method of claim 29 further comprising: programming more than one cell associated with an X-line by simultaneously activating at least two Y-lines.
- 33. (Original) The method of claim 32 wherein said at least two simultaneously activated Y-lines are associated with different Y-line groups.
- 34. (Original) The method of claim 29 wherein the memory array comprises passive element memory cells.
- 35. (Original) The method of claim 34 wherein the memory array comprises anti-fuse memory cells.
- 36. (Original) The method of claim 34 wherein the memory array comprises magnetoresistive memory cells.
- 37. (Original) The method of claim 29 wherein the memory array comprises EEPROM memory cells.
  - 38. (Currently Amended) An integrated circuit comprising:
  - a memory array including:
    - a plurality of X-lines disposed on at least one layer of the memory array; a plurality of Y-lines disposed on at least one other layer of the memory array; a plurality of non-volatile memory cells, each coupled to an associated one of the plurality of X-lines and an associated one of the plurality of Y-lines;
  - an X-line selection circuit for selecting within a first array block at least a first X-line group of at least two X-lines when in a read mode, and for selecting a lesser number of X-lines within at least the first X-line group when in a write mode; and

- a Y-line selection circuit for simultaneously selecting within the first array block in the read mode a first Y-line group of at least one Y-line and a second Y-line group of at least one Y-line, and for respectively coupling the selected first and second Y-line groups to respective first and second inputs of an associated sense amplifier circuit;
- wherein the associated sense amplifier circuit is responsive to an aggregate signal from memory cells associated with both the selected first X-line group and the selected first Y-line group, and responsive to an aggregate signal from memory cells associated with both the selected first X-line group and the selected second Y-line group.
- 39. (Original) The integrated circuit as recited in claim 38 further comprising a reference signal circuit operably coupled to the second input of the associated sense amplifier circuit.
- 40. (Original) The integrated circuit as recited in claim 38 wherein the first Y-line group and the second Y-line group each number but one Y-line.
- 41. (Original) The integrated circuit as recited in claim 38 wherein the associated sense amplifier circuit is configured to sense more than two levels of aggregate memory cell signal.
  - 42. (Original) The integrated circuit as recited in claim 38 wherein:
  - the X-line selection circuit is further configured for selecting, when in the read mode, a second X-line group of at least two X-lines simultaneously with selecting the first X-line group; and
  - the associated sense amplifier circuit is responsive to an aggregate signal from memory cells associated with the selected first X-line group and the selected first Y-line group and memory cells associated with the selected second X-line group and the selected first Y-line group, and responsive further to an aggregate signal from memory cells associated with the selected first X-line group and the selected second Y-line group and memory cells associated with the selected second X-line group and the selected second Y-line group.

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- 43. (Currently amended) The integrated circuit as recited in claim 38 wherein: the X-line selection circuit is further configured for selecting, when in the read mode, a third X-line group of at least two X-lines when whenever the first X-line group is not selected.
- 44. (Original) The integrated circuit as recited in claim 38 wherein the memory array comprises passive element memory cells.
- 45. (Original) The integrated circuit as recited in claim 44 wherein the memory array comprises anti-fuse memory cells.
- 46. (Original) The integrated circuit as recited in claim 38 wherein the memory array comprises EEPROM memory cells.
- 47. (Original) The integrated circuit as recited in claim 38 wherein the memory array comprises a three-dimensional memory array having more than one plane of memory cells disposed above a semiconductor substrate.
- 48. (Currently amended) The integrated circuit as recited in claim 47 wherein the first X-line group comprises X-lines disposed on more than one layer of the memory array.
- 49. (Currently amended) The integrated circuit as recited in claim 47 wherein the first X-line group comprises X-lines disposed only on a single layer of the memory array.
- 50. (Original) The integrated circuit as recited in claim 38 embodied in computer readable descriptive form suitable for use in design, test or fabrication of said integrated circuit.
  - 51. (Currently Amended) An integrated circuit comprising:
  - a memory array including:
    - a plurality of X-lines disposed on at least one layer of the memory array;
    - a plurality of Y-lines disposed on at least one other layer of the memory array;

line; and

- a plurality of non-volatile memory cells, each coupled to an associated one of the plurality of X-lines and an associated one of the plurality of Y-lines; means for programming individual memory cells associated with a first X-line group of at least one X-line within a first array block and further associated with a first Y-line group of at least one Y-line within the first array block until a desired aggregate memory cell read current is obtained when simultaneously selecting all the first group of X-lines and all the first group of Y-lines, at least one of the first X-line group and first Y-line group including more than one such X-line or Y-
- means for reading the memory array by simultaneously selecting all the first group of X-lines and all the first group of Y-lines and generating a signal responsive to the aggregate memory cell read signal conveyed on the first group of Y-lines.
- 52. (Original) The integrated circuit of claim 51 further comprising: means for programming more than one cell associated with an X-line by simultaneously activating at least two Y-lines.
- 53. (Original) The integrated circuit of claim 52 wherein said at least two simultaneously activated Y-lines are associated with different Y-line groups.
- 54. (Original) The integrated circuit of claim 51 wherein the memory array comprises passive element memory cells.
- 55. (Original) The integrated circuit of claim 54 wherein the memory array comprises anti-fuse memory cells.
- 56. (Original) The integrated circuit of claim 51 wherein the memory array comprises EEPROM memory cells.